

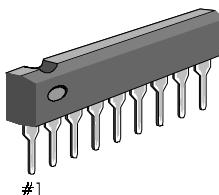
INTRODUCTION

The KA2220 is a monolithic integrated circuit consisting of a pre-amplifier and an ALC circuit for cassette tape recorders.

FEATURES

- Low noise amplifier
- Wide operating supply voltage range
 $V_{CC} = 3.5V \sim 14V$
- High output voltage
- Low distortion
- Wide ALC range
- Good ALC pair characteristic for stereo tape recorders

9-SIP



#1

ORDERING INFORMATION

Device	Package	Operating Temperature
KA2220	9-SIP	-20°C ~ +70°C

BLOCK DIAGRAM

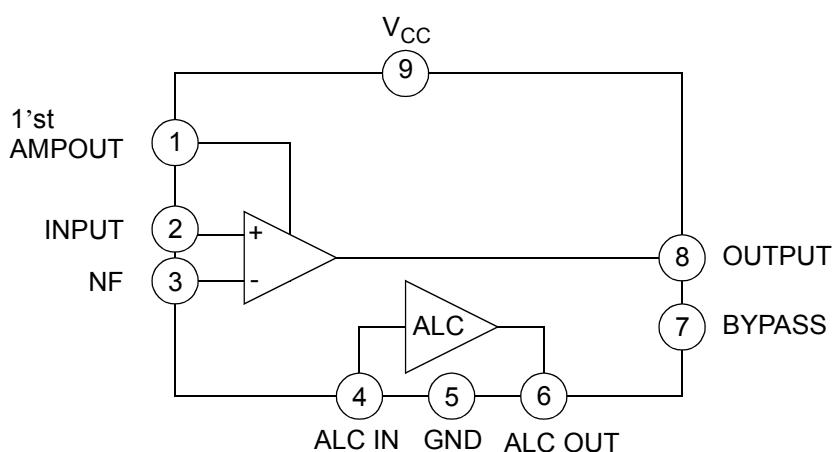


Figure 1.

ABSOLUTE MAXIMUM RATINGS (Ta = 25°C)

Characteristic	Symbol	Value	Unit
Supply voltage	V _{CC}	15	V
Power dissipation	P _D	200	mW
Operating temperature	T _{OPR}	- 20 ~ +70	°C
Storage temperature	T _{STG}	- 40 ~ +125	°C

ELECTRICAL CHARACTERISTICS(Ta = 25°C, V_{CC} = 5V, R_L = 5.1K, R_G = 600Ω, f = 1kHz, NAB, unless otherwise specified)

Characteristic	Symbol	Test Conditions	Min.	Typ.	Max.	Unit
Quiescent Circuit Current	I _{CCQ}	V _I = 0, ALC OFF	—	1.4	2.0	mA
Open Loop Voltage Gain	G _{VO}	—	66	69	—	dB
Closed Loop Voltage Gain	G _{VC}	V _O = 0.7 V	33	35	37	dB
Output Voltage	V _O	THD = 1 %	0.7	1.0	—	V
Total Harmonic Distortion	THD	V _O = 0.2 V	—	0.1	—	%
Input Resistance	R _I	—	60	100	—	KΩ
Equivalent Input Noise Voltage	V _{NI}	R _G = 2.2kΩ, NAB BW (-3dB) = 15Hz ~ 30kHz	—	1.0	—	μV
ALC Transistor Saturation Voltage	V _{SAT}	—	—	75	100	mV

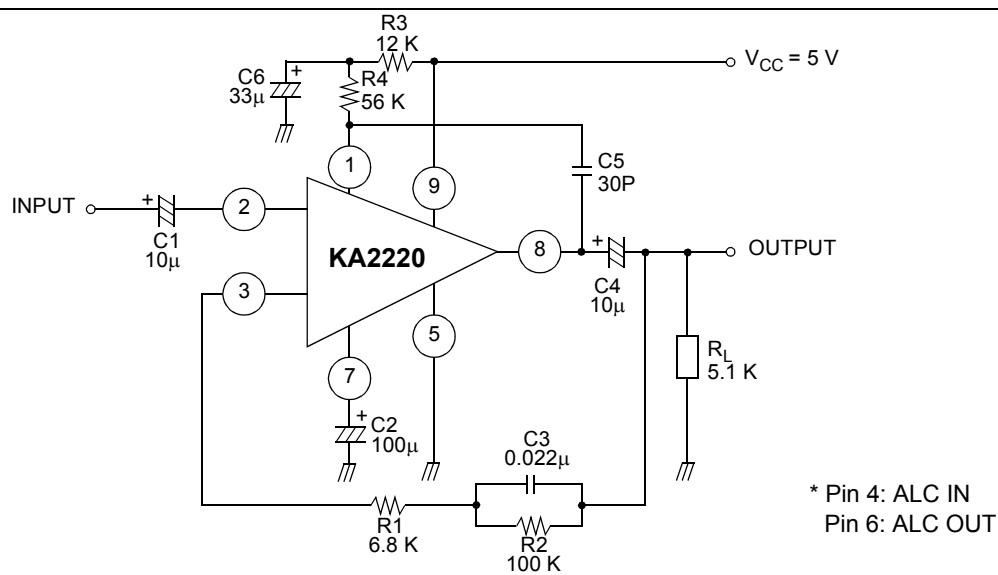
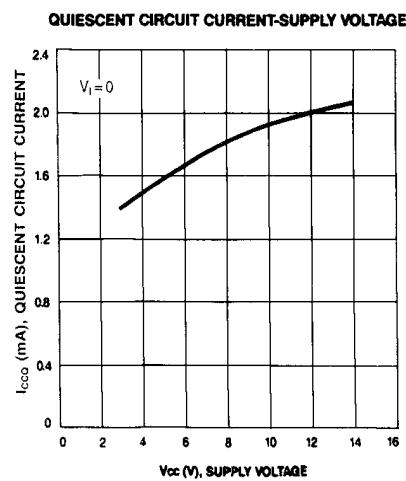
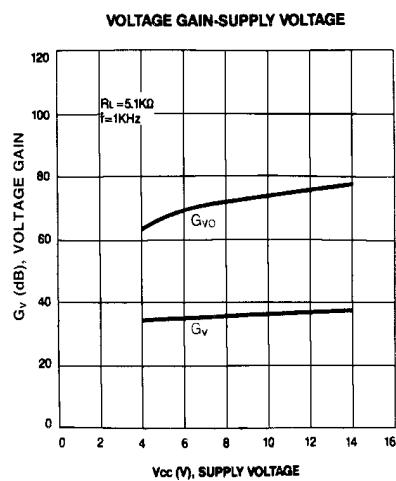
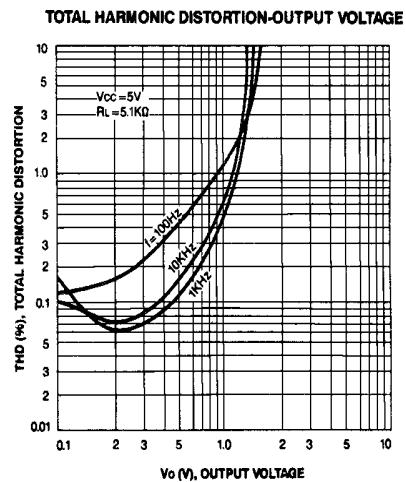
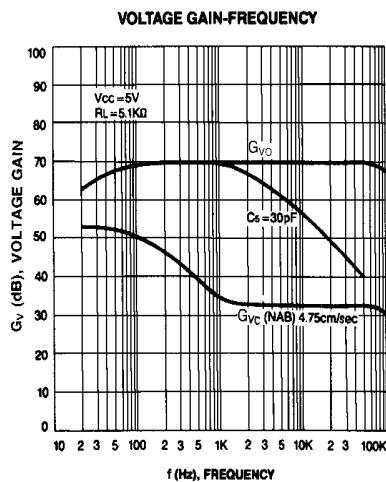
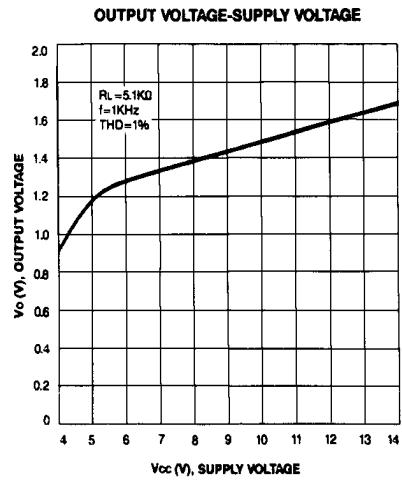
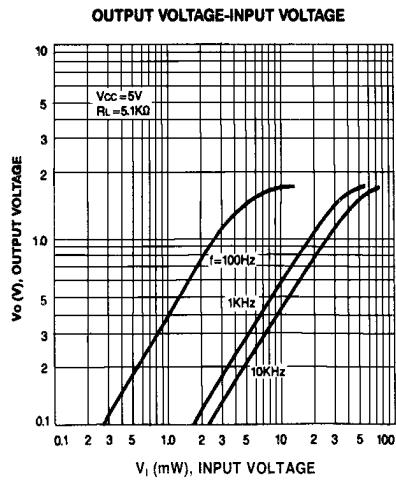
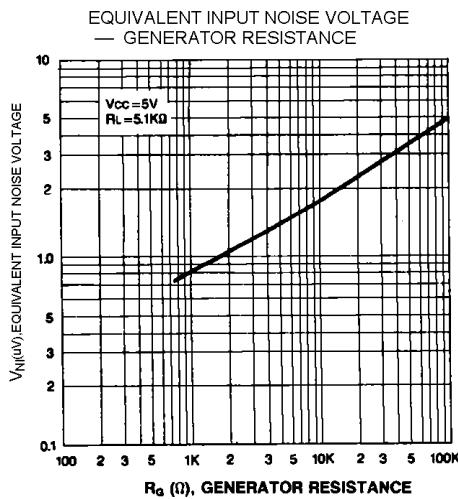
TEST CIRCUIT

Figure 2.





APPLICATION INFORMATION

ALC Grade Binning Table

Symbol	A_V (dB)		ALC Grade (dB)	
	Min.	Max.	Min.	Max.
KA2220 J	34	36	-16.0	-27.0
KA2220 M			-25.0	-34.0

External Components (Refer to test circuits)

C₁: Input coupling capacitor

The recommended value is 10 μF . If made too small the low frequency characteristics will change for the worse, and too large a capacitance value will increase the rising time when power is applied.

C₂: Bypass capacitor

A short emitter resistor on the AC, which prevents an AC signal from feedback from being input.

C₃: R₁, R₂: Equalizer network

The closed loop voltage gain is determined by these components in relation to the internal resistance at Pin 3.

C₄: Output coupling capacitor

C₂ is determined as follows:

$$C_4 = \frac{1}{2\pi \cdot f_L \cdot R_L}$$

f_L: low cut-off frequency

R_L: load resistance

C₅: Phase compensation capacitor.

Prevents high frequency oscillation by phase error when feedback is heavy.

C₆: Ripple filter for power supply

A large value is required to get an excellent ripple characteristic under the line operation, but it must be made smaller to shorten the starting time.

R_3 : Filter resistance

R_4 : Collector resistor of first stage transistor of the IC

Low voltage characteristic can be improved by adjusting this resistance.

ALC GRADE BINNING TEST CIRCUIT

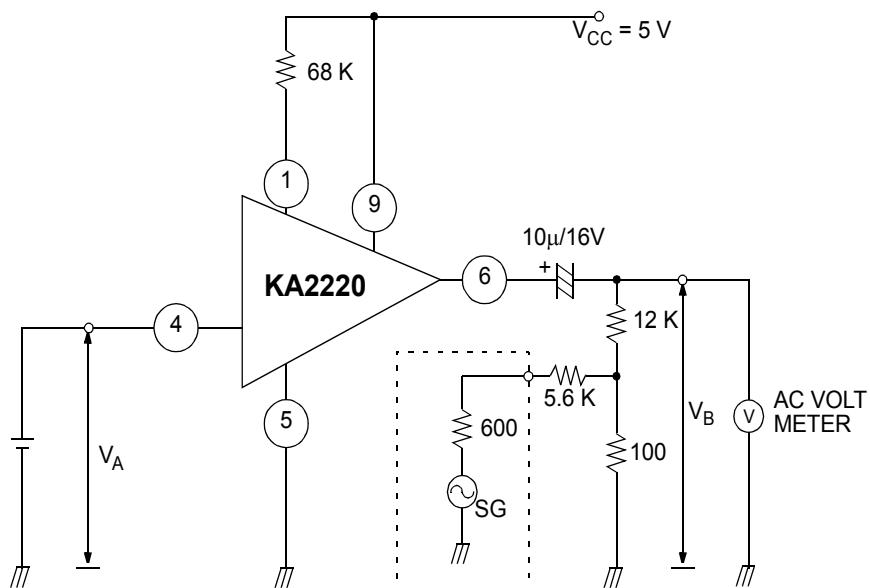


Figure 3.

Test condition: S.G. output level should be adjusted to be 13.8 mV of the AC voltmeter reading (V_B) when the D.U.T. is not connected to the test circuit ($V_{CC} = 5\text{ V}$, $V_A = 1.16\text{ V}$, $T_a = 25^\circ\text{C}$).

ALC RANK is defined as $\text{ALC-G.R} = 20 \log \frac{V_{B2}}{V_{B1}}$

where

V_{B1} : AC voltmeter reading when the D.U.T. is not connected,

V_{B2} : AC voltmeter reading when the D.U.T. is connected.

APPLICATION CIRCUIT

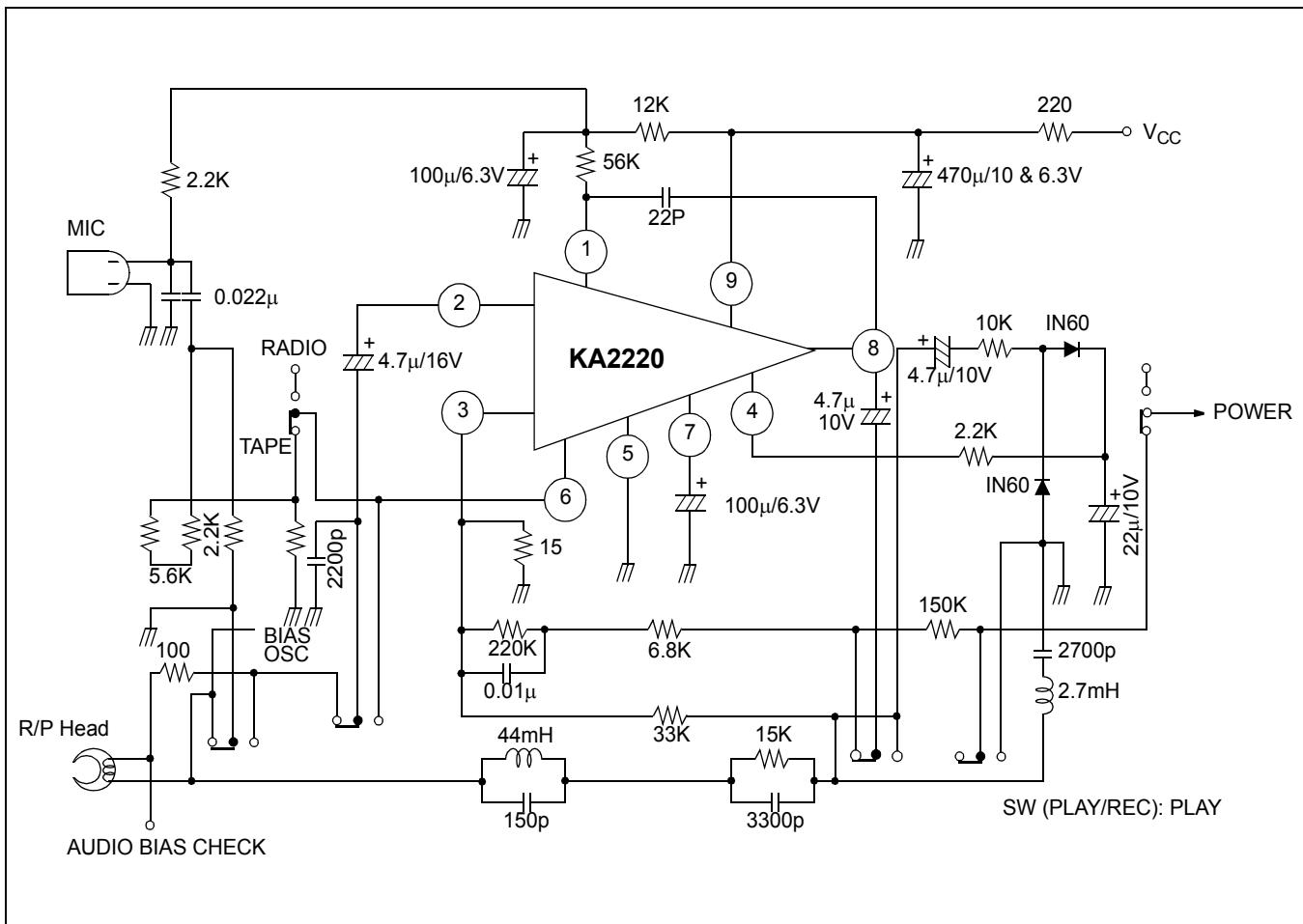


Figure 4.